H01J 37/28 (2006.01)

H01J 37/147 (2006.01)

(12)

CORRECTED EUROPEAN PATENT APPLICATION

(51) Int Cl.:

(15) Correction information:

Corrected version no 1 (W1 A2) Corrections, see

Bibliography INID code(s) 54

(48) Corrigendum issued on:

13.07.2011 Bulletin 2011/28

(43) Date of publication:

11.05.2011 Bulletin 2011/19

(21) Application number: 10014424.5

(22) Date of filing: 09.11.2010

G01N 23/203 (2006.01)

H01J 37/295 (2006.01)

(84) Designated Contracting States:

AL AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO RS SE SI SK SM TR

Designated Extension States:

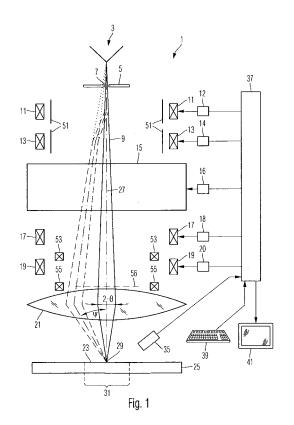
BA ME

(30) Priority: 09.11.2009 DE 102009052392

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(54) SACP method and particle optical system for performing the method

A SACP (selected area channeling pattern) method comprising: directing a beam (9) of charged particles onto an object surface (23) of an object (25) using a particle optical system (1); and detecting intensities of particles emanating from the object; wherein the method comprises: (a1) adjusting an excitation of a second beam deflector (17,19) for adjusting an impingement location (29) of the beam on the object surface; (a2) adjusting an excitation of a first beam deflector (11,13) for adjusting an angle (Ψ) of incidence of the beam on the object surface without changing the impingement location and detecting the intensity; and (a3) repeating the adjusting of the excitation of the first beam deflector for adjusting the angle of incidence without changing the impingement location such that a corresponding intensity is detected (35) for each of at least 100 different angles of incidence at the same impingement location. The application also relates to a charged particle optical system (1) for performing the method.



EP 2 320 217 A8